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## nSpec Version 0.24.1.1

**Release Date:** 11 Jun 2024


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## Overview

Patch release nSpec v0.24.1.1 includes two minor feature updates to nView image tile view and Device Inspection analysis exports.

## Upgrading to v0.24.1.1

 Library Update Not Required

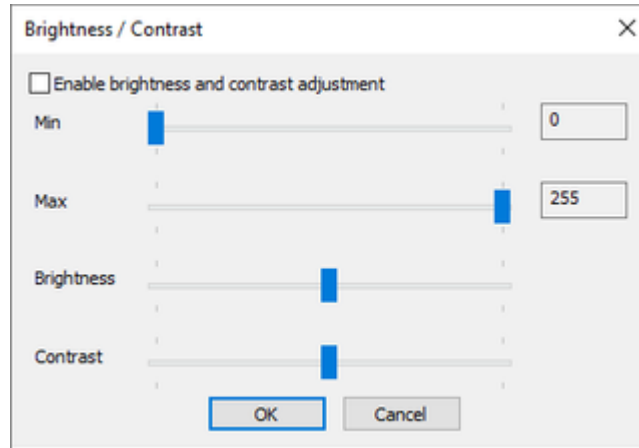
If upgrading from a version more than 1 release prior, please reference all intermediate release notes for upgrade steps *for each version*.

## New Features

### Highlights

#### **NSPEC-8478: Add Brightness/Contrast dialog to nView**

Adjust the brightness and contrast of any image in nView by accessing the **Brightness / Contrast** dialog at **nView defect view > Display > Adjust brightness / contrast ...**



### NSPEC-8515: New Device Inspection analysis parameter toggles file export output

New Device Inspection analysis parameter, **Export Files**, when enabled, continues the existing behavior of exporting the following files: KLARF, CML, CSV, and `DefectMosaicic.jpg` files. When **Export Files** is disabled, these export files are NOT generated. These exports will be deprecated in 2025.

### New Features Changelog

T	Key	Release Notes Summary
	NSPEC-8478	Add Brightness/Contrast dialog to nView
	NSPEC-8515	New Device Inspection analysis parameter toggles file export output

2 issues